



INEMI

International Electronics Manufacturing Initiative

HFR-Free Leadership Program

*Program Manager:
Stephen Tisdale, Intel*

HFR-Free Signal Integrity
*Chair: Stephen Hall, Intel
Co-chair: David Senk, Cisco*

HFR-Free PCB Materials
Chair: John Davignon, Intel

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Agenda

- ***Project Introduction***
- ***PCB Material WG***
 - ***Strategy***
 - ***Areas of Concern / Methodology***
 - ***Benefits***
- ***Signal Integrity WG***
 - ***Strategy***
 - ***Areas of Concern***
- ***Summary***
 - ***Project Status / Timeline***

Problem Statement

- Many of the HF laminates on the market have shown a reduction in performance margin from the FR-4 laminates being used today
- This margin loss is in both the thermo-mechanical and electrical performance
- The critical electrical properties of available HFR-free dielectrics make high-speed bus design problematic without increasing the cost of the system
- The flame retardants currently used vary among manufacturers, resulting in wider fluctuation of vendor to vendor PCB electrical performance compared to FR4 designs

iNEMI HFR-Free Leadership Program

Consortium Objectives

- 1. Identify technology readiness, supply chain capability, and reliability characteristics for “HFR-free” alternatives to conventional printed circuit board materials and assemblies**
 - Spans electrical and mechanical properties
 - Includes assessing if board/system design modifications can overcome material property limitations
- 2. Define technology limits for HFR-free materials across all market segments**
 - Initial focus is on client platforms (desktop, notebook)
 - Goal is to drive laminate supplier slash sheet content

HFR-free Technology Leadership Project



**Stephen Tisdale, Intel – Chair
HFR-Free Leadership Program**

**HFR-Free PCB Materials
(Chair: John Davignon – Intel)**

Identify key thermo-mechanical performance characteristics and determine if they are in the critical path for the HFR-free PCB material transition.

**HFR-Free Signal Integrity
(Chair: Stephen Hall - Intel
Co-Chair: David Senk - Cisco)**

Ensure there is no degradation of electrical signals in HFR-free PCB materials, base on investigation of permittivity and loss as well as how they are impacted by moisture absorption in new HFR-free materials.





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iNEMI HF PCB Materials

Chair: John Davignon, Intel

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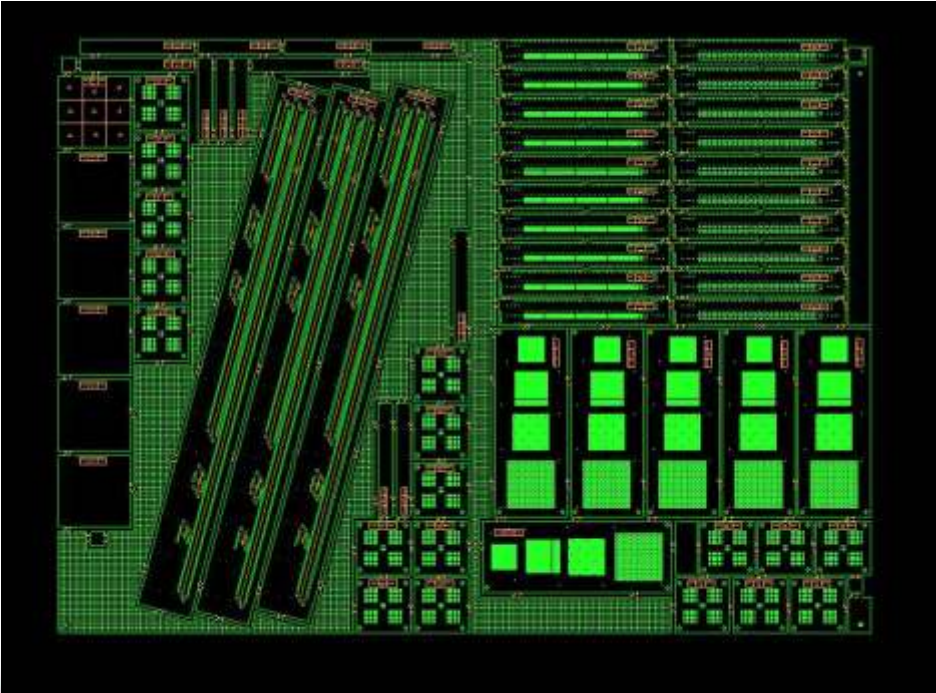
iNEMI HF PCB Materials WG Strategy

- **Define and implement quantifiable data into the HF Laminate Suppliers Datasheets that will assist in material selection by users.**
- **Define a “Test Suite Methodology” which meets the quality and reliability requirements of the chosen market segments**
- **Ensure the Industry Laminate Suppliers have the capability and capacity to support the industry HF laminate requirements**

Test Suite Methodology

Test Methods Under Evaluation

Glass Transition Temperature (Tg)	Stiffness/Flexural Strength
Decomposition Temperature (Td)	Pad Adhesion (CBP/Hot Pin Pull)
Coefficient of Thermal Expansion (x,y,z)	Interconnect Stress Test (IST)
Moisture absorption	Conductive Anodic Filament (CAF)
Rework (Pad Peeling)	Lead Free Reflow Test: Delamination
Permittivity (Dk)	Charpy Impact Test
Total Loss (Df)	Simulated Reflow Test



10 Layer Mobile Stack-up

	Description	Layer Type	Thickness
Layer 1	Plated 1/2 oz Cu		1.6 mils
	Prepreg		3 mils - 1 ply 1080
Layer 2	Unplated 1 oz Cu		1.3 mils
	Core		4 mil core - 1 ply 2116
Layer 3	Unplated 1 oz Cu		1.3 mils
	Prepreg		4.2 mils - 1 ply 2116
Layer 4	Unplated 1 oz Cu		1.3 mils
	Core		4 mil core - 1 ply 2116
Layer 5	Unplated 1 oz Cu		1.3 mils
	Prepreg		4.2 mils - 1 ply 2116
Layer 6	Unplated 1 oz Cu		1.3 mils
	Core		4 mil core - 1 ply 2116
Layer 7	Unplated 1 oz Cu		1.3 mils
	Prepreg		4.2 mils - 1 ply 2116
Layer 8	Unplated 1 oz Cu		1.3 mils
	Core		4 mil core - 1 ply 2116
Layer 9	Unplated 1 oz Cu		1.3 mils
	Prepreg		3 mils - 1 ply 1080
Layer 10	Plated 1/2 oz Cu		1.6 mils

48.2



Benefits of the Consortia

- **We are changing the way that data is reported on the Laminate datasheets.**
 - The test methods will be precisely defined
 - The test methods will be performed on a “product like” construction for more relevant data
- **The data reported will enable:**
 - A true comparison of material properties and responses between laminates
 - OEM/ODM’s to set envelopes for the material properties based on the market/BU sector that mitigate risk factors for that sector
 - PCB Designers to pick cost effective laminate materials that are suitable to their products/market segment
 - Method of directing Laminate Suppliers how to improve laminates by specific properties or responses





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iNEMI HF Signal Integrity WG

Chair: Stephen Hall, Intel
Co-Chair: David Senk, Cisco

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iNEMI HF Signal Integrity WG Strategy

Identify HFR-free electrical “envelopes” required by each company in the consortium

Develop a common measurement methodology
Characterize available HF dielectrics & map into requirements

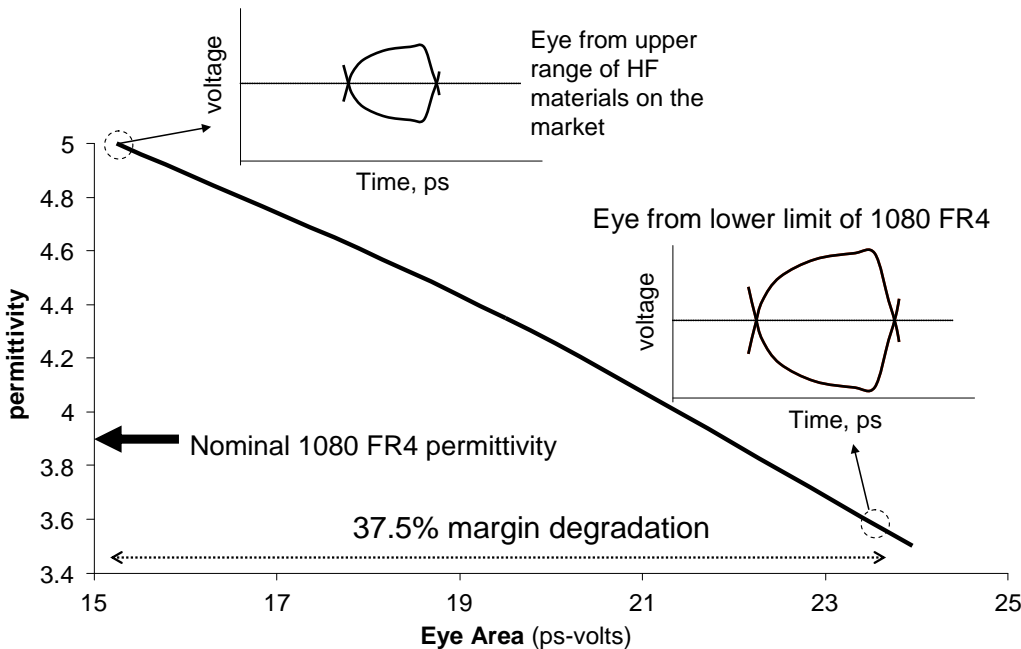
Communicate requirements to the material vendors so they know what the industry wants



Performance of HF PCB vs. FR4

✓ **HFR-free PCB materials on the market tend to have higher permittivity (Dk) values than FR4**

- ✓ HFR-free Dk ~ 4.2 – 5.0 (1080)
- ✓ FR4 Dk ~ 3.6-3.9 (1080)



Simulation of three coupled 10" 50Ω microstrip lines; dielectric thickness varied to maintain Z_0 ; layout rules similar to DDR buses (W/S/W=4/12/4)

✓ **Higher permittivity (Dk) reduces bus performance**

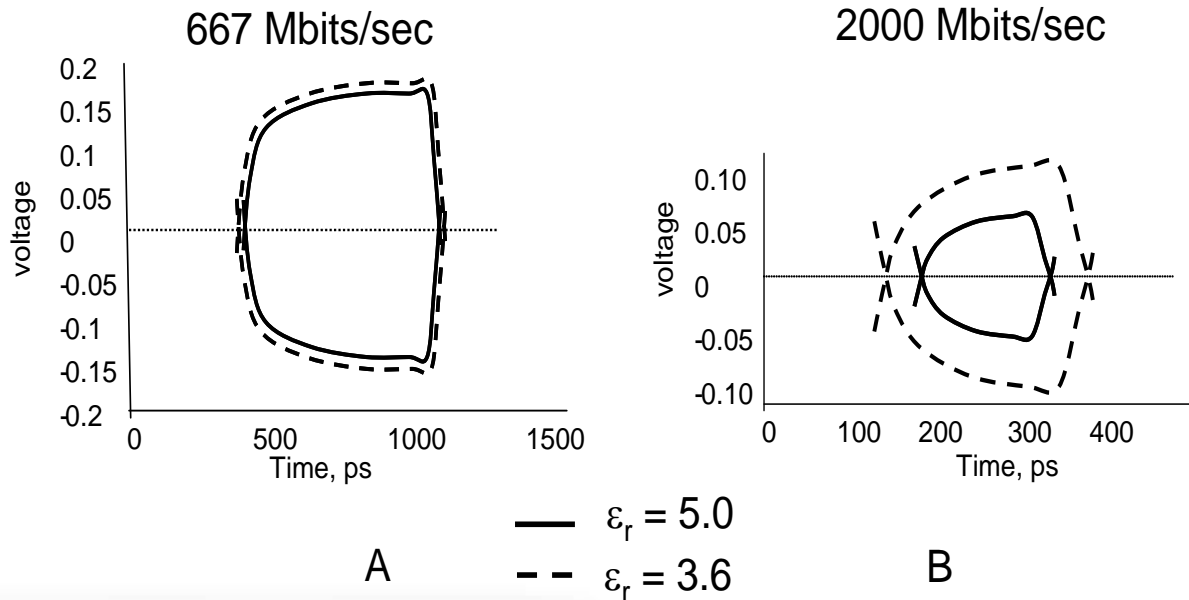
- Thicker layers for same Z_0 increases crosstalk
- High crosstalk drives increased trace separation & more layers (increased cost)

✓ **HFR-free losses tend to be better than FR4 & help compensate for crosstalk for some buses**

Scaling HFR-free bus speeds

✓ Margin reductions gets worse for faster buses

- HFR-free materials with high permittivity may be adequate for lower speed buses, but can be problematic at higher speeds
- FR4 also places limitations on high-speed buses, but HFR-free exacerbates problems on crosstalk dominated buses like DDR
- HFR-free PCBs can make it more difficult for buses to scale with Moore's Law



Simulation of three coupled 10" 50Ω microstrip lines with layout rules similar to DDR buses (WSW=4/12/4)

Critical Electrical Parameters

✓ **In addition to Permittivity, other critical electrical parameters of HFR-free materials must be assessed**

- Each new formulation of flame retardants will have unique electrical parameters → non-standard electrical behavior
- Must ensure all critical electrical parameters remain within acceptable bounds

Parameter	Other names	Design influences
Permittivity	Dk, ϵ_r, dielectric constant	Characteristic impedance, Propagation velocity, crosstalk
Loss tangent	Df, $\tan\delta$, dissipation factor	Signal attenuation
Moisture absorption	Environmental effects, humidity	When dielectric materials absorb water, Dk & Df increase.



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Summary

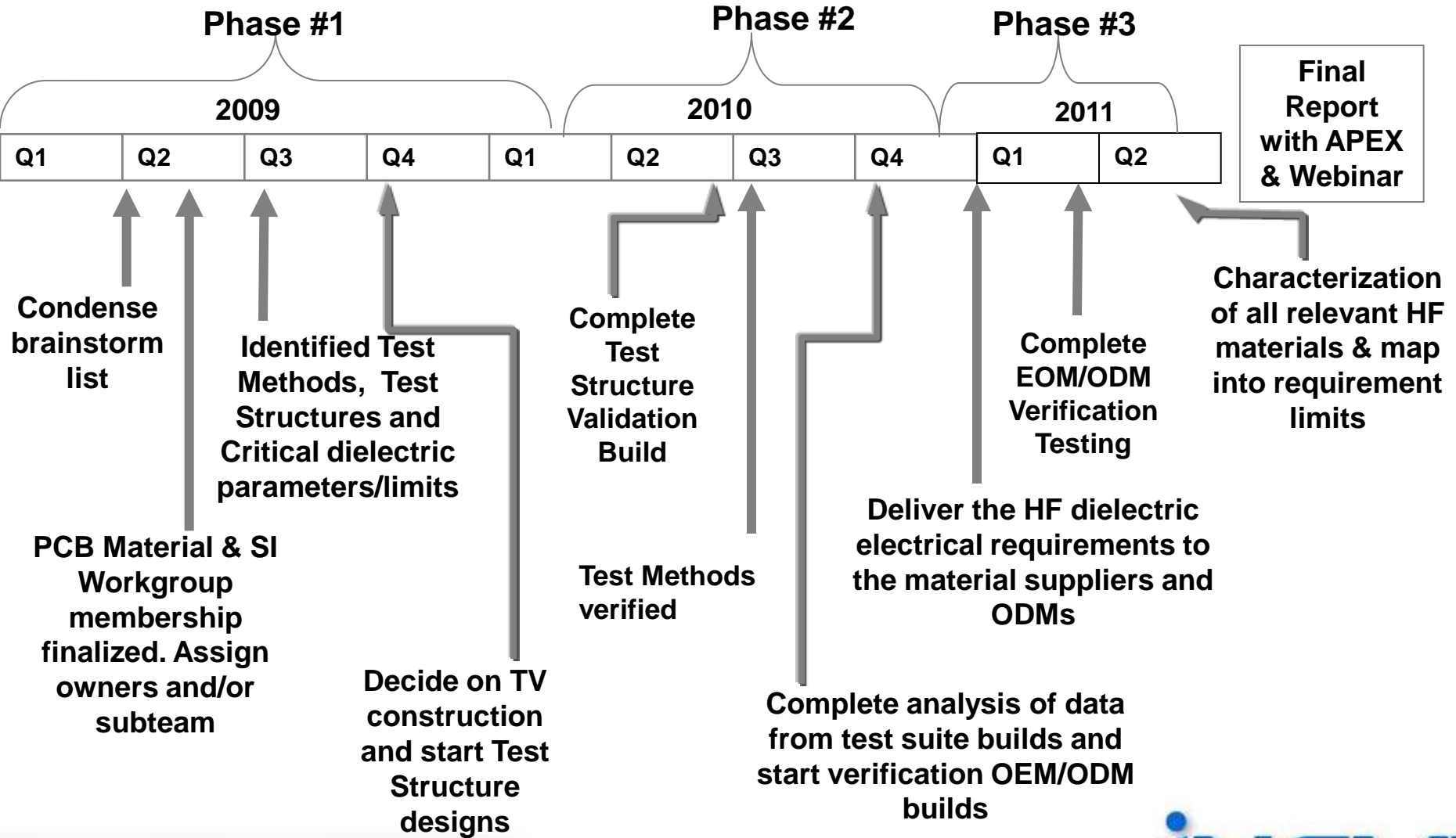
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iNEMI HF-Free Leadership Consortia Status

- The initial Test Methods, Test Structures designs, Test Vehicle lay out and construction for the Test Suite Methodology have been completed and in the process of being validated
- Nine different Laminate materials have been chosen for the evaluation (6 HF and 3 FR-4 baseline)
- The Proof of Concept Test Suite validation builds completed
- Common measurement method developed by CISCO to characterize the critical parameters (S3 method)
- Analysis of data underway to validate Test Methods and associated Test Structures, including repeatability and reproducibility at 3 test houses
- Plans in place to complete Phase #2 TV builds, test and data analysis by the end of Q4'10
- Validation of the S3 method currently under way
 - S3 measurements compared to split post resonator measurements (SPR assumed to be the golden standard for accuracy)
 - Initial results show adequate accuracy for Dk, Df evaluation ongoing
- Round robin initiated to get Lab-Lab variation, 7 companies to act as “test houses” for the evaluation of the HFR-free materials



Proposed Timeline



Summary

- **HFR-free dielectric materials on the market today have higher permittivity than FR4**
- **HFR-free PCBs come at a cost**
 - Reduced bus margins (especially on DDR)
 - Increased difficulty in speed scaling
 - Possibly increased layer count leading to more \$\$\$\$
- **Limits can be placed on the permittivity so that FR4 and HFR-free PCBs are interchangeable for a single design**
- **The HFSIWG is currently evaluating many HFR-free materials on the market to create a data-base for member companies to design with**

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Discussion